

This Page Is Inserted by IFW Operations
and is not a part of the Official Record

BEST AVAILABLE IMAGES

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images may include (but are not limited to):

- BLACK BORDERS
- TEXT CUT OFF AT TOP, BOTTOM OR SIDES
- FADED TEXT
- ILLEGIBLE TEXT
- SKEWED/SLANTED IMAGES
- COLORED PHOTOS
- BLACK OR VERY BLACK AND WHITE DARK PHOTOS
- GRAY SCALE DOCUMENTS

IMAGES ARE BEST AVAILABLE COPY.

**As rescanning documents *will not* correct images,
please do not report the images to the
Image Problem Mailbox.**

Refine Search

Search Results -

Terms	Documents
(711/206 711/213).ccls.	946

Database:

US Pre-Grant Publication Full-Text Database
 US Patents Full-Text Database
 US OCR Full-Text Database
 EPO Abstracts Database
 JPO Abstracts Database
 Derwent World Patents Index
 IBM Technical Disclosure Bulletins

Search:

L6

Search History

DATE: Monday, June 28, 2004 [Printable Copy](#) [Create Case](#)

Set Name	Query	Hit Count	Set Name result set
<i>DB=USPT; PLUR=YES; OP=ADJ</i>			
<u>L6</u>	711/206,213.ccls.	946	<u>L6</u>
<u>L5</u>	714/37,38.ccls.	1027	<u>L5</u>
<u>L4</u>	712/227,207.ccls.	709	<u>L4</u>
<u>L3</u>	L2 and l1	11	<u>L3</u>
<u>L2</u>	717/130,136,139,140.ccls.	585	<u>L2</u>
<u>L1</u>	profile and execute and translation and physical and logical and record\$	821	<u>L1</u>

END OF SEARCH HISTORY

Refine Search

Search Results -

Terms	Documents
(151/151).ccls.	0

Database:

US Pre-Grant Publication Full-Text Database
 US Patents Full-Text Database
 US OCR Full-Text Database
 EPO Abstracts Database
 JPO Abstracts Database
 Derwent World Patents Index
 IBM Technical Disclosure Bulletins

Search:

L24

Search History

DATE: Monday, June 28, 2004 [Printable Copy](#) [Create Case](#)

Set Name	Query	Hit Count	Set Name result set
<i>DB=USPT; PLUR=YES; OP=ADJ</i>			
L24	717/151/158.ccls.	0	L24
L23	L22 and I10	0	L23
L22	717/136,137,138,139,140.ccls.	545	L22
L21	L20 and I10	0	L21
L20	717/127,128,129,130,131,132,133,134,135.ccls.	748	L20
<i>DB=USPT,TDBD; PLUR=YES; OP=ADJ</i>			
L19	profil\$ near8 (distinc\$ or differ\$ or separat\$) near9 (address\$ near5 (translat\$ or conver\$))	2	L19
<i>DB=TDBD; PLUR=YES; OP=ADJ</i>			
L18	profile\$ near4 address\$ near4 (conver\$ or transfer\$ or tmaslat\$)	0	L18
<i>DB=DWPI; PLUR=YES; OP=ADJ</i>			
L17	profile\$ near4 address\$ near4 (conver\$ or transfer\$ or tmaslat\$)	1	L17
<i>DB=JPAB; PLUR=YES; OP=ADJ</i>			

<u>L16</u> profile\$ near4 address\$ near4 (conver\$ or transfer\$ or ttnaslat\$)	1	<u>L16</u>
<i>DB=EPAB; PLUR=YES; OP=ADJ</i>		
<u>L15</u> profile\$ near4 address\$ near4 (conver\$ or transfer\$ or ttnaslat\$)	0	<u>L15</u>
<i>DB=USOC; PLUR=YES; OP=ADJ</i>		
<u>L14</u> profile\$ near4 address\$ near4 (conver\$ or transfer\$ or ttnaslat\$)	0	<u>L14</u>
<i>DB=PGPB; PLUR=YES; OP=ADJ</i>		
<u>L13</u> profile\$ near4 address\$ near4 (conver\$ or transfer\$ or ttnaslat\$) and (pyhsical\$ near5 address\$)	0	<u>L13</u>
<i>DB=USPT; PLUR=YES; OP=ADJ</i>		
<u>L12</u> L10 and logical\$	7	<u>L12</u>
<u>L11</u> L10 and (pyhsical\$ near5 address\$)	0	<u>L11</u>
<u>L10</u> profile\$ near4 address\$ near4 (conver\$ or transfer\$ or ttnaslat\$)	13	<u>L10</u>
<u>L9</u> profile\$ near4 (distinc\$ or differ\$) near8 address\$ near4 (trans\$ or conver\$)	0	<u>L9</u>
<u>L8</u> l6 and (translat\$ near4 address\$)	1	<u>L8</u>
<u>L7</u> L6 and (profil\$ or address\$)	1	<u>L7</u>
<u>L6</u> 6047363.pn.	1	<u>L6</u>
<u>L5</u> l3 and (address\$ near5 translat\$)	0	<u>L5</u>
<u>L4</u> L3 and profil\$ and address\$	0	<u>L4</u>
<u>L3</u> 6043363.PN.	1	<u>L3</u>
<u>L2</u> 6763452.pn.	0	<u>L2</u>
<u>L1</u> 6763452.pn.	0	<u>L1</u>

END OF SEARCH HISTORY

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

Welcome
United States Patent and Trademark Office

Help FAQ Terms IEEE Peer Review

Quick Links

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

Your search matched **1** of **1047691** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard**1 TIME: Tools for Input/output and Memory Evaluation***Richardson, K.J.; Flynn, M.J.;*

System Sciences, 1992. Proceedings of the Twenty-Fifth Hawaii International Conference on , Volume: i , 7-10 Jan. 1992

Pages:58 - 66 vol.1

[\[Abstract\]](#)[\[PDF Full-Text \(524 KB\)\]](#)**IEEE CNF**

Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**
RELEASE 1.7Welcome
United States Patent and Trademark Office[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

Your search matched **0** of **1047691** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**Results:****No documents matched your query.** **Print Format**[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**
RELEASE 1.7Welcome
United States Patent and Trademark Office

» Search

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)**Welcome to IEEE Xplore®**

- ☐ [Home](#)
- ☐ [What Can I Access?](#)
- ☐ [Log-out](#)

Tables of Contents

- ☐ [Journals & Magazines](#)
- ☐ [Conference Proceedings](#)
- ☐ [Standards](#)

Search

- ☐ [By Author](#)
- ☐ [Basic](#)
- ☐ [Advanced](#)

Member Services

- ☐ [Join IEEE](#)
- ☐ [Establish IEEE Web Account](#)
- ☐ [Access the IEEE Member Digital Library](#)

[Print Format](#)[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)Your search matched **0** of **1047691** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**Results:****No documents matched your query.**